

E2

0.10

0.05

Ф

BOTTOM VIEW

CAB

C NOTE 3

QFN20 4x4, 0.5P

DATE 19 FEB 2010

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
 DIMENSION & APPLIES TO PLATED TERMINAL
 AND IS MEASURED BETWEEN 0.15 AND 0.30 MM
 FROM TERMINAL TIP.
 COPLANARITY APPLIES TO THE EXPOSED PAD
 AS WELL AS THE TERMINALS.

	MILLIMETERS		
DIM	MIN	MAX	
Α	0.80	1.00	
A1		0.05	
А3	0.20 REF		
b	0.20	0.30	
D	4.00 BSC		
D2	2.60	2.80	
E	4.00 BSC		
E2	2.60	2.80	
е	0.50 BSC		
K	0.20		
L	0.35	0.45	
L1	0.00	0.15	

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code

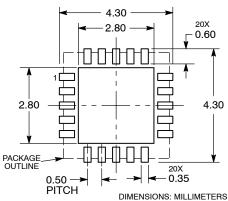
= Assembly Location

= Wafer Lot L = Year W = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G", may or not be present.

MOUNTING FOOTPRINT



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